

# GSMDB2116S

## 20V N+P Dual Channel MOSFETs

### Product Description

These N+P dual Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

### Features

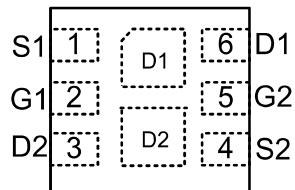
- N-Channel  
20V, 5A,  $R_{DS(ON)}=40m\Omega$ @ $V_{GS}=4.5V$
- P-Channel  
-20V, -4.7A,  $R_{DS(ON)}=95m\Omega$ @ $V_{GS}=-4.5V$
- Fast switching
- Suit for -1.8V/1.8V Gate Drive Applications
- Green Device Available
- DFN2X2-6L package design

### Applications

- Notebook
- Load Switch
- Networking
- Hand-held Instruments

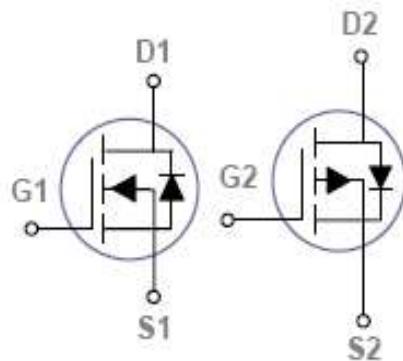
### Packages & Pin Assignments

GSMDB2116SFF (DFN2X2-6L)

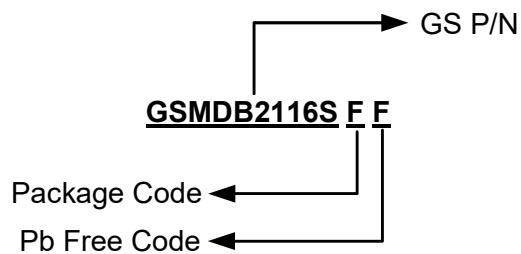


Top Views

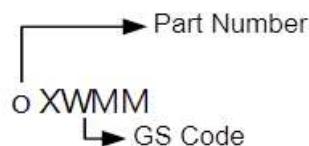
Pin	Description
1	Source 1
2	Gate 1
3	Drain 2
4	Source 2
5	Gate 2
6	Drain 1



## Ordering Information



## Marking Information



Part Number	Package	Part Marking	Quantity
GSMDB2116SFF	DFN2X2-6L	oXWMM	4000pcs

## Absolute Maximum Ratings

T<sub>c</sub>=25°C Unless otherwise noted

Symbol	Parameter	Typical		Unit
		N-Channel	P-Channel	
V <sub>DS</sub>	Drain-Source Voltage	20	-20	V
V <sub>GS</sub>	Gate-Source Voltage	±10	±10	V
I <sub>D</sub>	Continuous Drain Current(T <sub>J</sub> =150°C)	5	-4.7	A
	T <sub>c</sub> =25°C			
	T <sub>c</sub> =100°C	4.1	-3.9	
I <sub>DM</sub>	Pulsed Drain Current (Note 1)	15.2	-10	A
P <sub>D</sub>	Power Dissipation	T <sub>c</sub> =25°C Derate above 25°C	1.56 0.01	W W/°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to +150		°C
T <sub>STG</sub>	Storage Temperature Range	-55 to +150		°C
R <sub>θJA</sub>	Thermal Resistance-Junction to Ambient	80		°C/W
R <sub>θJC</sub>	Thermal Resistance-Junction to Case	15		°C/W

Note 1: Repetitive Rating: Pulsed width limited by maximum junction temperature.

## Electrical Characteristics (N-Channel)

T<sub>J</sub>=25°C Unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	20			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA		0.02		V/°C
V <sub>GS(th)</sub>	Gate Threshold Voltage		0.3	0.6	1.0	V
△V <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA		-2		mV/°C
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±10V			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V			1	
		V <sub>DS</sub> =16V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C			10	uA
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current			5	A
I <sub>SM</sub>	Pulsed Source Current				10	
R <sub>DS(on)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =4.5V, I <sub>D</sub> =3A	30	40		
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =2A	42	55		mΩ
		V <sub>GS</sub> =1.8V, I <sub>D</sub> =1.5A	55	70		
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =2A		4.4		S
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =1A			1	V
<b>Dynamic</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =10V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =3A		5.8	10	
Q <sub>gs</sub>	Gate-Source Charge			0.6	1.5	nC
Q <sub>gd</sub>	Gate-Drain Charge			1.5	3	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz		315	600	
C <sub>oss</sub>	Output Capacitance			50	80	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			40	60	
t <sub>d(on)</sub>	Turn-On Time (Note 2,3)	V <sub>DD</sub> =10V, I <sub>D</sub> =1A, V <sub>GS</sub> =4.5V, R <sub>G</sub> =25Ω		2.9	6	
t <sub>r</sub>				8.4	16	ns
t <sub>d(off)</sub>	Turn-Off Time (Note 2,3)			19.2	38	
t <sub>f</sub>				5.6	12	

Note 2: The data tested by pulsed, pulse width≤300us, duty cycle≤2%.

Note 3: Essentially independent of operating temperature.

## Electrical Characteristics (P-Channel)

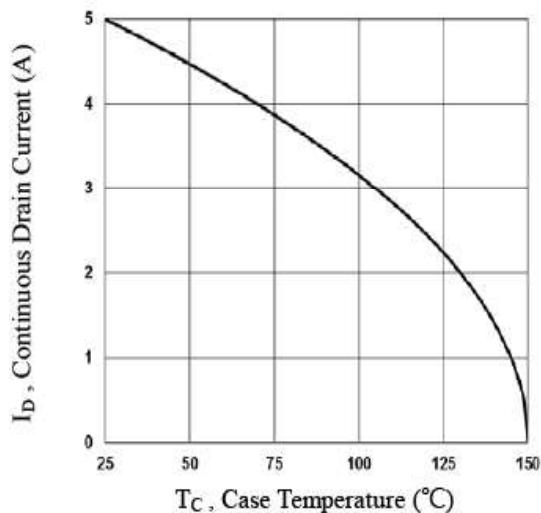
T<sub>J</sub>=25°C Unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA	-20			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =-1mA		-0.01		V/°C
V <sub>GS(th)</sub>	Gate Threshold Voltage		-0.3	-0.6	-1.0	V
△V <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA		3		mV/°C
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±10V			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-20V, V <sub>GS</sub> =0V			-1	
		V <sub>DS</sub> =-16V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C			-10	uA
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current			-4.7	A
I <sub>SM</sub>	Pulsed Source Current				-9.4	
R <sub>DS(on)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-3A	80	95		
		V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-2A	109	125		mΩ
		V <sub>GS</sub> =-1.8V, I <sub>D</sub> =-1A	148	161		
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =-10V, I <sub>D</sub> =-1A	2.2			S
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =-1A			-1	V
<b>Dynamic</b>						
Q <sub>g</sub>	Total Gate Charge		4.8	10		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =-10V, V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-2A	0.5	1		nC
Q <sub>gd</sub>	Gate-Drain Charge		1.9	4		
C <sub>iss</sub>	Input Capacitance		350	510		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =-15V, V <sub>GS</sub> =0V, f=1MHz	65	95		pF
C <sub>rss</sub>	Reverse Transfer Capacitance		50	75		
t <sub>d(on)</sub>	Turn-On Time (Note 2,3)		3.5	7		
t <sub>r</sub>		V <sub>DD</sub> =-10V, I <sub>D</sub> =-1A, V <sub>GS</sub> =-4.5V, R <sub>G</sub> =25Ω	12.6	24		ns
t <sub>d(off)</sub>	Turn-Off Time (Note 2,3)		32.6	62		
t <sub>f</sub>			8.4	16		

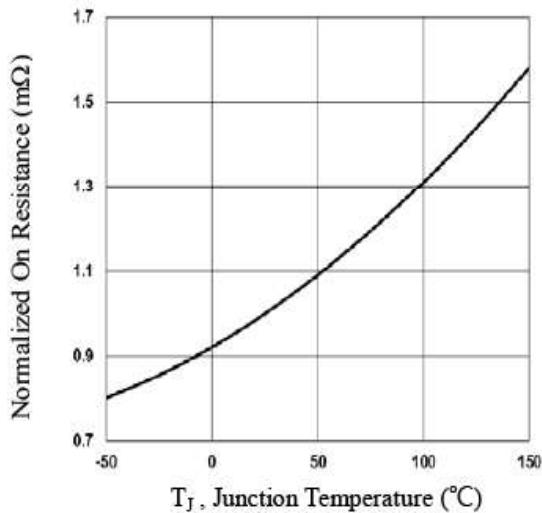
Note 2: The data tested by pulsed, pulse width ≤300us, duty cycle ≤2%.

Note 3: Essentially independent of operating temperature.

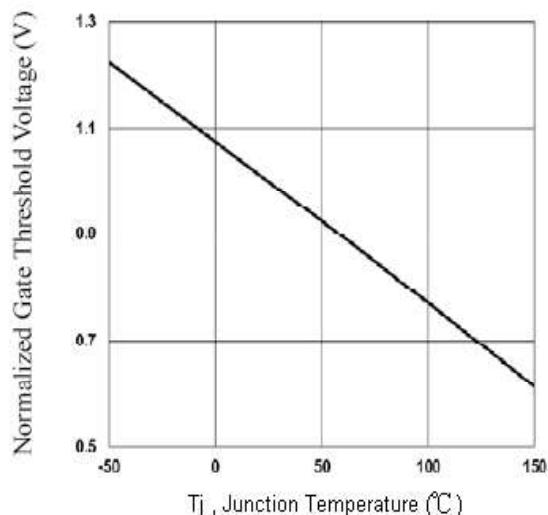
## Typical Performance Characteristics (N-Channel)



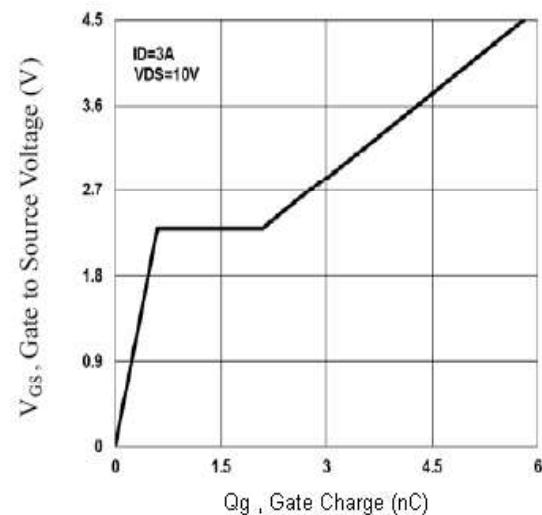
**Fig.1** Continuous Drain Current vs.  $T_c$



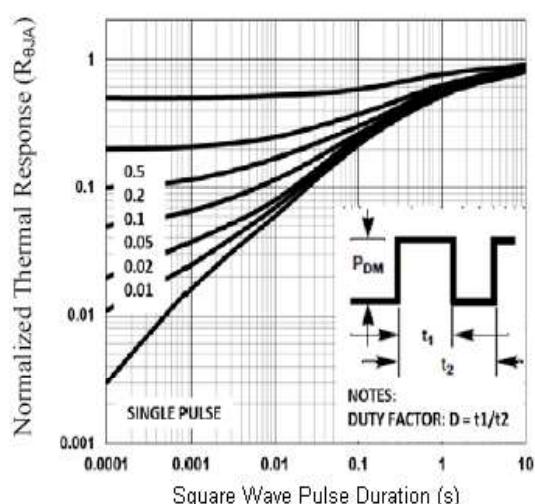
**Fig.2** Normalized RDS(on) vs.  $T_j$



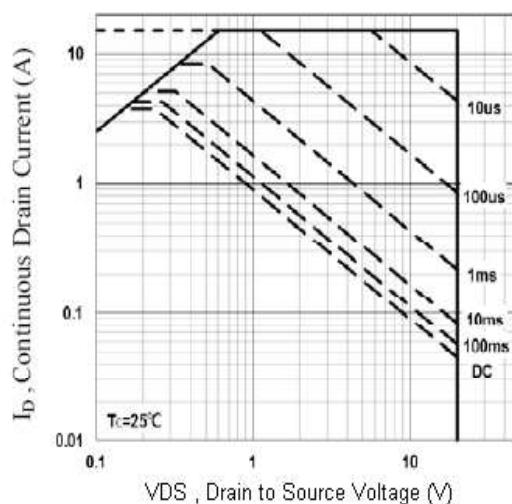
**Fig.3** Normalized  $V_{th}$  vs.  $T_j$



**Fig.4** Gate Charge Waveform



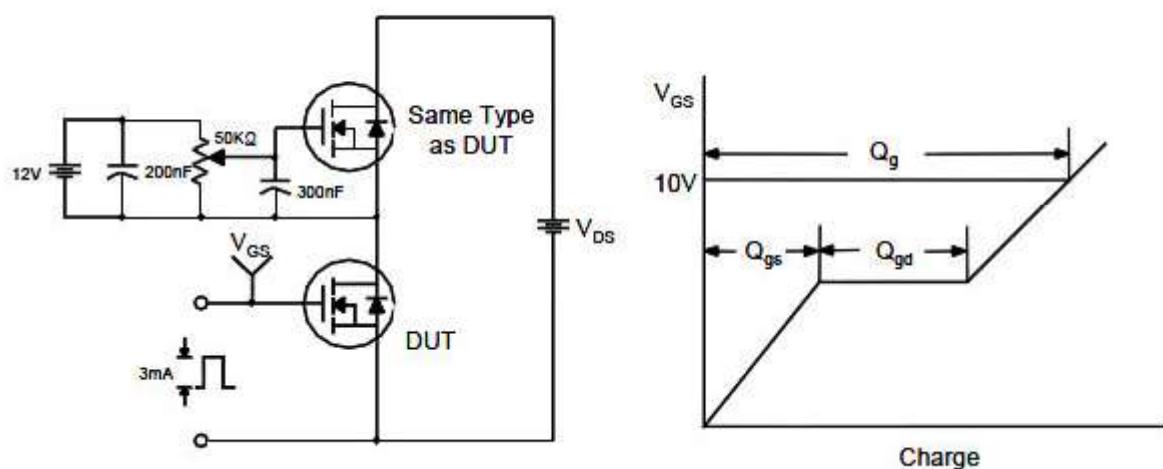
**Fig.5** Normalized Transient Impedance



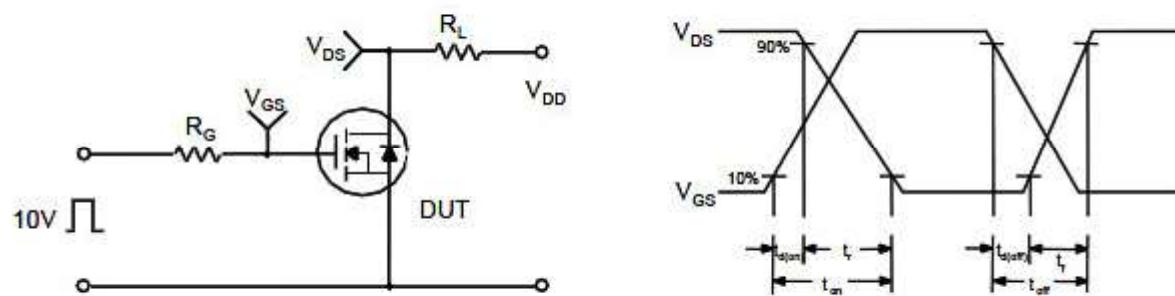
**Fig.6** Maximum Safe Operation Area

## Typical Performance Characteristics (N-Channel)

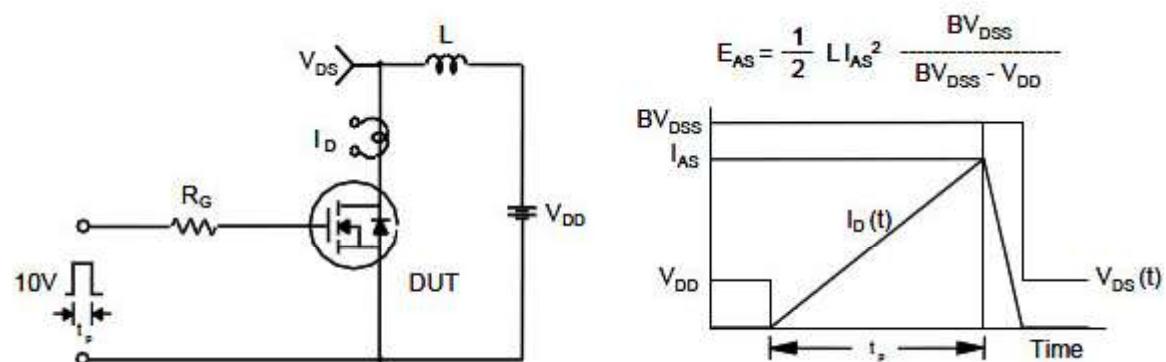
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



## Typical Performance Characteristics (P-Channel)

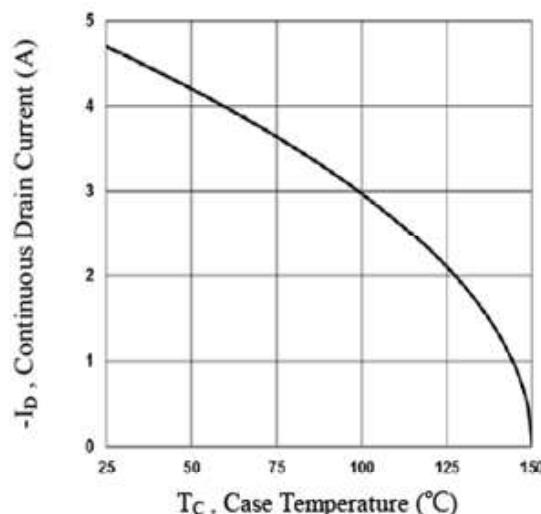


Fig.7 Continuous Drain Current vs. T<sub>C</sub>

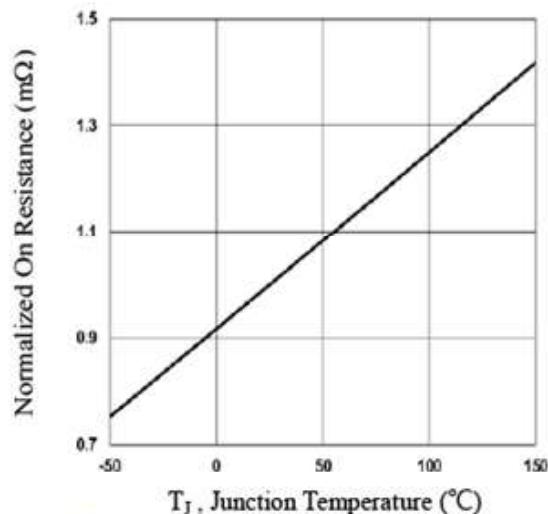


Fig.8 Normalized RDS(ON) vs. T<sub>J</sub>

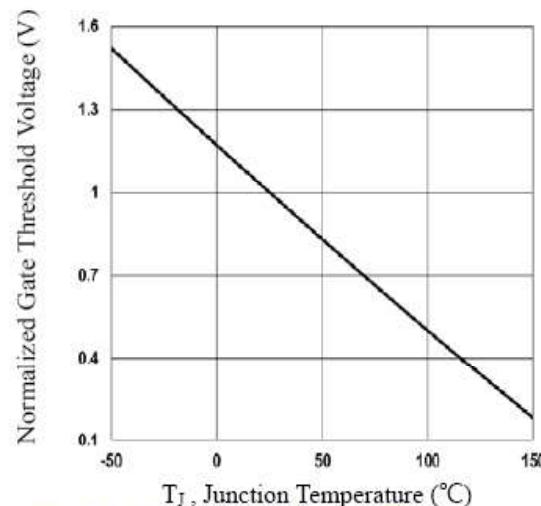


Fig.9 Normalized V<sub>th</sub> vs. T<sub>J</sub>

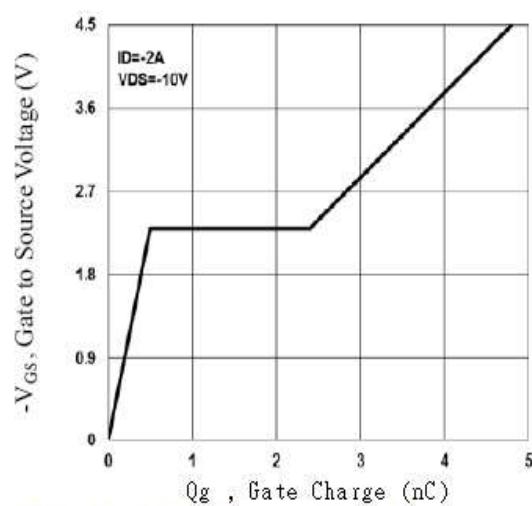


Fig.10 Gate Charge Waveform

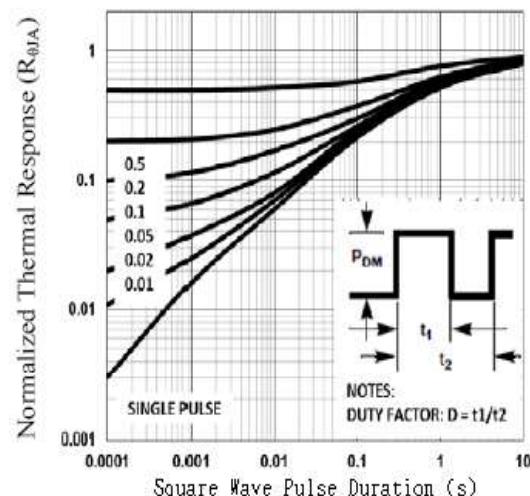


Fig.11 Normalized Transient Impedance

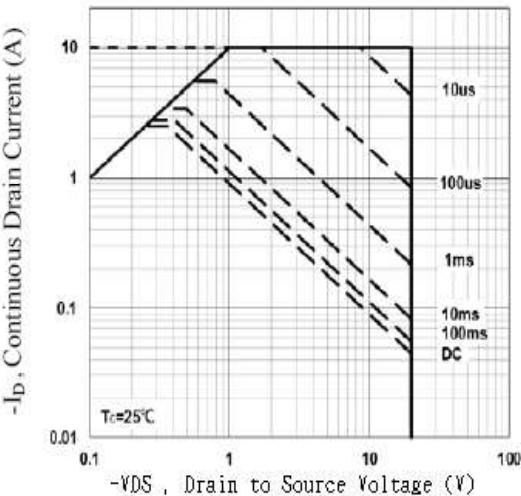
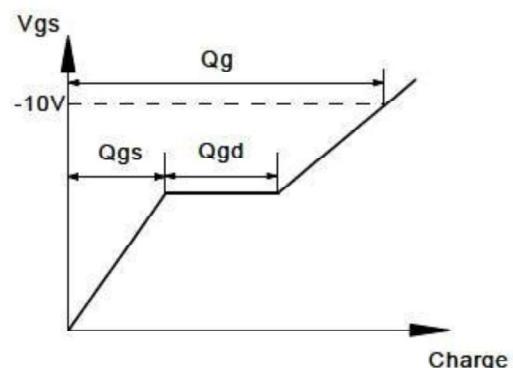
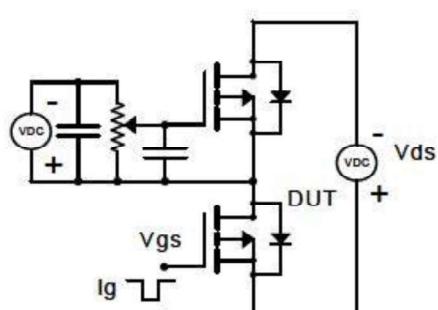


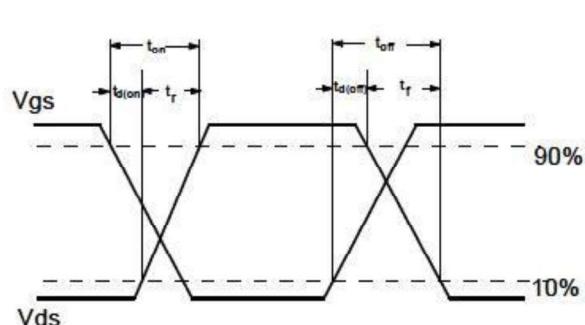
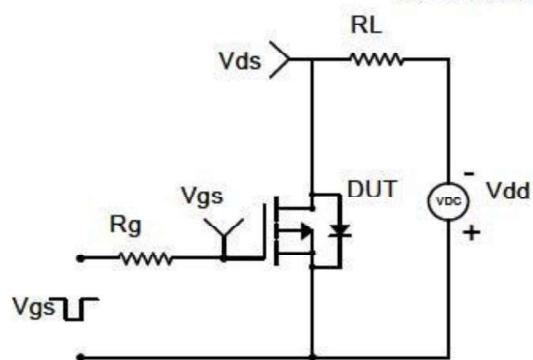
Fig.12 Maximum Safe Operation Area

## Typical Performance Characteristics (P-Channel)

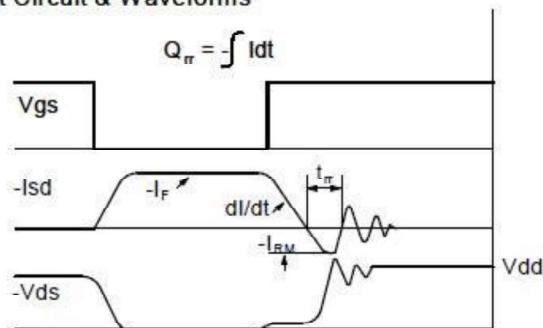
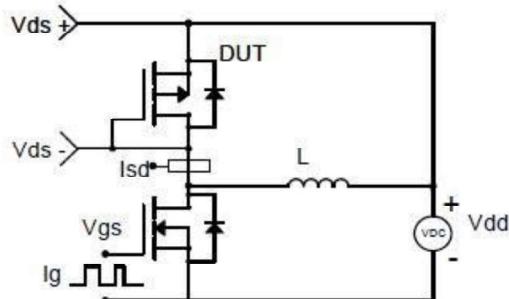
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

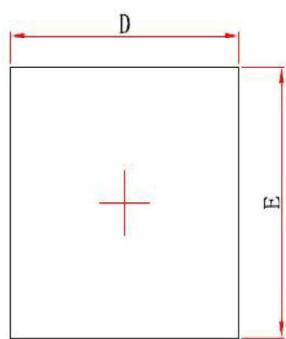


Diode Recovery Test Circuit & Waveforms

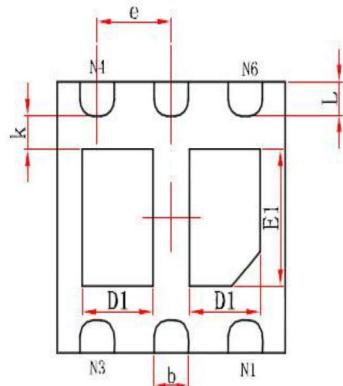


## Package Dimension

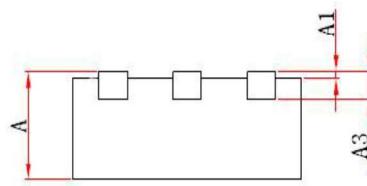
### DFN2X2-6L



Top View



Bottom View



Side View

### Dimensions

SYMBOL	Millimeters		Inches	
	MIN	MAX	MIN	MAX
A	0.700/0.800	0.800/0.900	0.028/0.031	0.031/0.035
A1	0.000	0.050	0.000	0.002
A3	0.203 (REF)		0.008 (REF)	
D	1.924	2.076	0.076	0.082
E	1.924	2.076	0.076	0.082
D1	0.520	0.720	0.020	0.028
E1	0.900	1.100	0.035	0.043
k	0.200 (MIN)		0.008 (MIN)	
b	0.250	0.350	0.010	0.014
e	0.650 (TYP)		0.026 (TYP)	
L	0.174	0.326	0.007	0.013

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